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Terms	Documents
Bayesian with prior with probability with distributions	12

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<u>L1</u>	Bayesian with prior with probability with distributions	12	<u>L1</u>
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☐ 1. Document ID: US 20040215425 A1

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L1: Entry 1 of 12

File: PGPB

Oct 28, 2004

PGPUB-DOCUMENT-NUMBER: 20040215425

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040215425 A1

TITLE: Method and system for estimation of quantities corrupted by noise and use of estimates in decision making

PUBLICATION-DATE: October 28, 2004

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Cherkassky, Dmitry	Voorhees	NJ	US	

US-CL-CURRENT: 702/189

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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☐ 2. Document ID: US 20040210417 A1

L1: Entry 2 of 12

File: PGPB

Oct 21, 2004

PGPUB-DOCUMENT-NUMBER: 20040210417

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040210417 A1

TITLE: Method and apparatus for randomized verification of neural nets

PUBLICATION-DATE: October 21, 2004

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Zakrzewski, Radoslaw Romuald	South Burlington	VT	US	

US-CL-CURRENT: 702/181

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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☐ 3. Document ID: US 20040078232 A1

L1: Entry 3 of 12

File: PGPB

Apr 22, 2004

PGPUB-DOCUMENT-NUMBER: 20040078232

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040078232 A1

TITLE: System and method for predicting acute, nonspecific health events

PUBLICATION-DATE: April 22, 2004

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Troiani, John S.	Maple Grove	MN	US	

US-CL-CURRENT: 705/2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 4. Document ID: US 20030143520 A1

L1: Entry 4 of 12

File: PGPB

Jul 31, 2003

PGPUB-DOCUMENT-NUMBER: 20030143520

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030143520 A1

TITLE: Gene discovery for the system assignment of gene function

PUBLICATION-DATE: July 31, 2003

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Hood, Leroy E.	Seattle	WA	US	
Siegel, Andrew F.	Shoreline	WA	US	
Ideker, Trey E.	Cambridge	MA	US	

US-CL-CURRENT: 435/4; 702/19, 703/11

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 5. Document ID: US 20030133615 A1

L1: Entry 5 of 12

File: PGPB

Jul 17, 2003

PGPUB-DOCUMENT-NUMBER: 20030133615

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030133615 A1

TITLE: Method and apparatus for improving image appearance

PUBLICATION-DATE: July 17, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Bern, Marshall W.	San Carlos	CA	US	
Goldberg, David	Palo Alto	CA	US	

US-CL-CURRENT: 382/225; 382/228, 382/254

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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☐ 6. Document ID: US 20020099594 A1

L1: Entry 6 of 12

File: PGPB

Jul 25, 2002

PGPUB-DOCUMENT-NUMBER: 20020099594

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020099594 A1

TITLE: Method and apparatus for determining one or more statistical estimators of customer behavior

PUBLICATION-DATE: July 25, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Heard, Nicholas	London		GB	

US-CL-CURRENT: 705/10; 705/39

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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☐ 7. Document ID: US 20020095259 A1

L1: Entry 7 of 12

File: PGPB

Jul 18, 2002

PGPUB-DOCUMENT-NUMBER: 20020095259

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020095259 A1

TITLE: Multiparameter analysis for drug response and related methods

PUBLICATION-DATE: July 18, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Hood, Leroy E.	Seattle	WA	US	
Siegel, Andrew F.	Shoreline	WA	US	

US-CL-CURRENT: 702/19; 435/7.1

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMMC	Draw. De
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☐ 8. Document ID: US 6381555 B1

L1: Entry 8 of 12

File: USPT

Apr 30, 2002

US-PAT-NO: 6381555

DOCUMENT-IDENTIFIER: US 6381555 B1

TITLE: Measurement system

DATE-ISSUED: April 30, 2002

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sewell; Roger Fane	Newnham			GB

US-CL-CURRENT: 702/181; 356/335, 702/128, 702/29

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMMC	Draw. De
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☐ 9. Document ID: US 5910655 A

L1: Entry 9 of 12

File: USPT

Jun 8, 1999

US-PAT-NO: 5910655

DOCUMENT-IDENTIFIER: US 5910655 A

**\*\* See image for Certificate of Correction \*\***

TITLE: Reducing interferences in elemental mass spectrometers

DATE-ISSUED: June 8, 1999

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Skilling; John	Cambridge			GB

US-CL-CURRENT: 250/281; 250/282

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMMC	Draw. De
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☐ 10. Document ID: US 5539704 A

L1: Entry 10 of 12

File: USPT

Jul 23, 1996

US-PAT-NO: 5539704

DOCUMENT-IDENTIFIER: US 5539704 A

TITLE: Bayesian sequential Gaussian simulation of lithology with non-linear data

DATE-ISSUED: July 23, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Doyen; Philippe M.	Thames Ditton			GB2
Den Boer; Lennert D.	Middlesex			GB2

US-CL-CURRENT: 367/73; 367/14, 367/15, 702/14, 702/181, 703/6

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. D.
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☐ 11. Document ID: EP 1197899 A1

L1: Entry 11 of 12

File: EPAB

Apr 17, 2002

PUB-NO: EP001197899A1

DOCUMENT-IDENTIFIER: EP 1197899 A1

TITLE: Method and apparatus for determining one or more statistical estimators of customer behaviour

PUBN-DATE: April 17, 2002

INVENTOR-INFORMATION:

NAME	COUNTRY
HEARD, NICHOLAS	GB

US-CL-CURRENT: 81/477; 164/338.1, 173/176, 194/344, 285/377

INT-CL (IPC): G06 F 17/60

EUR-CL (EPC): G06F017/60

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. D.
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☐ 12. Document ID: WO 9941662 A1

L1: Entry 12 of 12

File: EPAB

Aug 19, 1999

PUB-NO: WO009941662A1

DOCUMENT-IDENTIFIER: WO 9941662 A1

TITLE: MEASUREMENT SYSTEM

PUBN-DATE: August 19, 1999

INVENTOR-INFORMATION:

NAME	COUNTRY
SEWELL, ROGER FANE	GB

INT-CL (IPC): G06 F 9/44; G01 N 15/14

EUR-CL (EPC): G01N015/14

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. Ds
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<u>L1</u>	Bayesian with prior with probability with distributions	12	<u>L1</u>

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☐ 1. Document ID: US 20020099594 A1

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L2: Entry 1 of 2

File: PGPB

Jul 25, 2002

PGPUB-DOCUMENT-NUMBER: 20020099594

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020099594 A1

TITLE: Method and apparatus for determining one or more statistical estimators of customer behavior

PUBLICATION-DATE: July 25, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Heard, Nicholas	London		GB	

US-CL-CURRENT: 705/10; 705/39

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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☐ 2. Document ID: EP 1197899 A1

L2: Entry 2 of 2

File: EPAB

Apr 17, 2002

PUB-NO: EP001197899A1

DOCUMENT-IDENTIFIER: EP 1197899 A1

TITLE: Method and apparatus for determining one or more statistical estimators of customer behaviour

PUBN-DATE: April 17, 2002

INVENTOR-INFORMATION:

NAME	COUNTRY
HEARD, NICHOLAS	GB

US-CL-CURRENT: 81/477; 164/338.1, 173/176, 194/344, 285/377

INT-CL (IPC): G06 F 17/60

EUR-CL (EPC): G06F017/60

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KIMC	Draw. De
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Terms	Documents
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Example: optical <and> (fiber <or> fibre) <in> ti

3) Limit the results by selecting Search Options.

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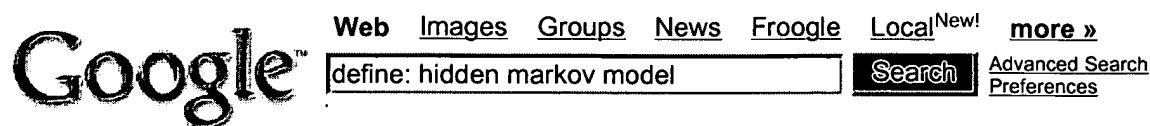

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## Web

### Definitions of **Hidden Markov Model** on the Web:

A probabilistic model used to align and analyze sequence datasets by generalization from a sequence profile.

[www.dddmag.com/scripts/glossary.asp](http://www.dddmag.com/scripts/glossary.asp)

Statistical modeling of the various pronunciations possible, or acoustic references of a word (or phoneme or expression depending on the case). The Markov models technique is used in most automatic speech recognition systems on the market. Cf. grammar

[www.telisma.com/gb\\_htdocs/apgprod07.htm](http://www.telisma.com/gb_htdocs/apgprod07.htm)

A probabilistic model consisting of a number of interconnecting states. HMMs encode full domain alignments. They are essentially linear chains of match, delete or insert states.

[bioinf.uta.fi/xml/courses/glossary/glossary-items.xml](http://bioinf.uta.fi/xml/courses/glossary/glossary-items.xml)

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